

FIG. 2

FIG. 3

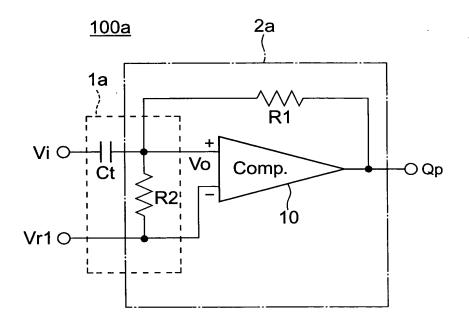


FIG. 4

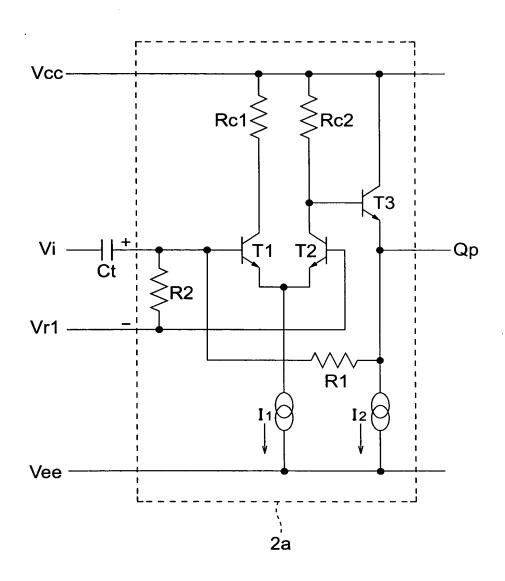
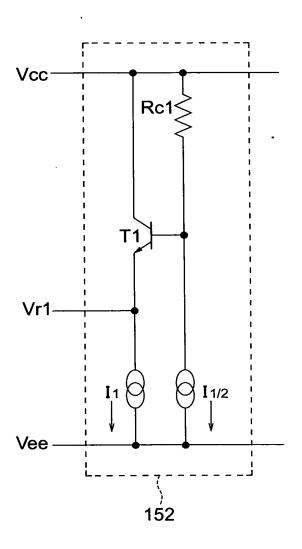


FIG. 5



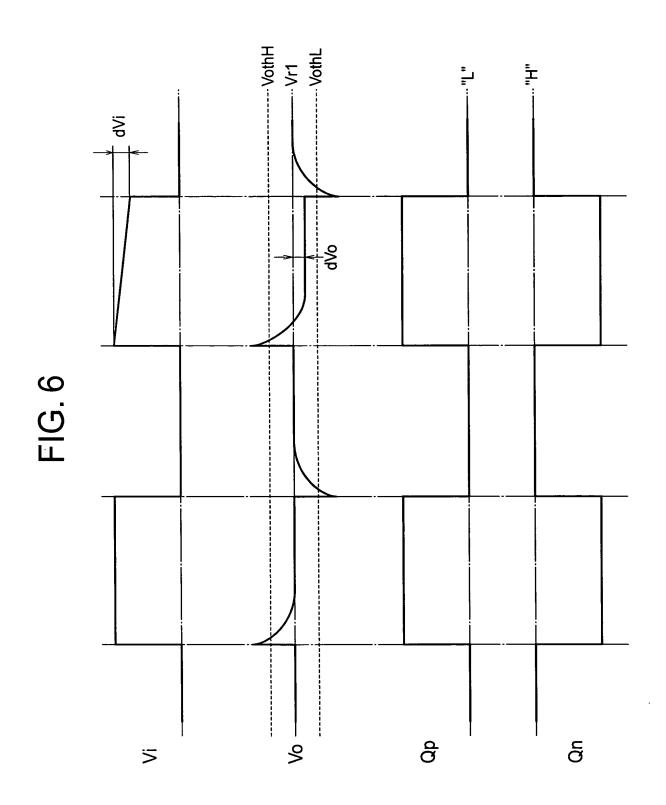
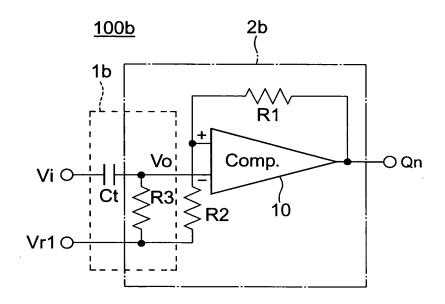


FIG. 7



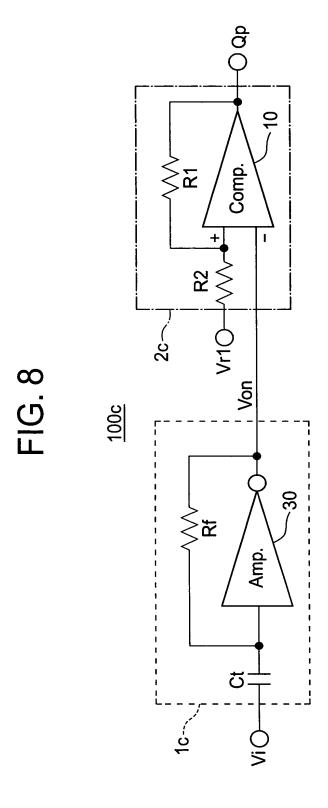
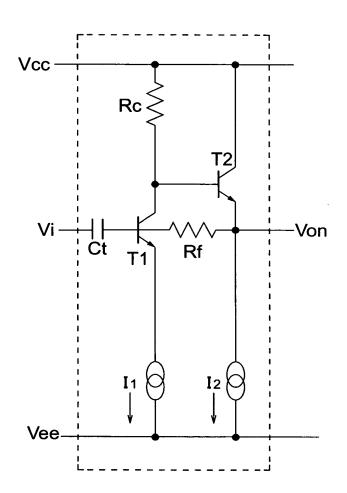
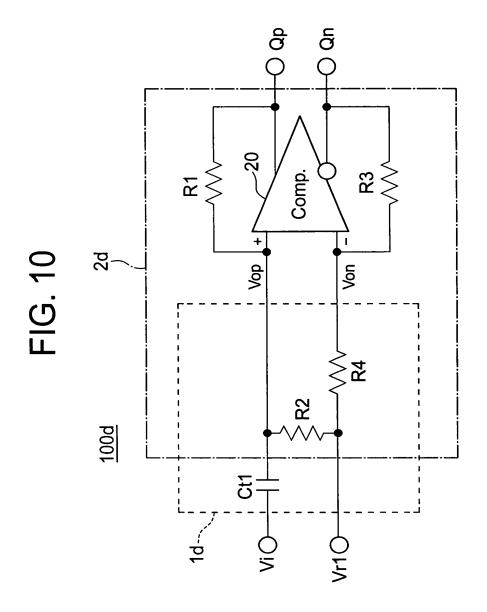
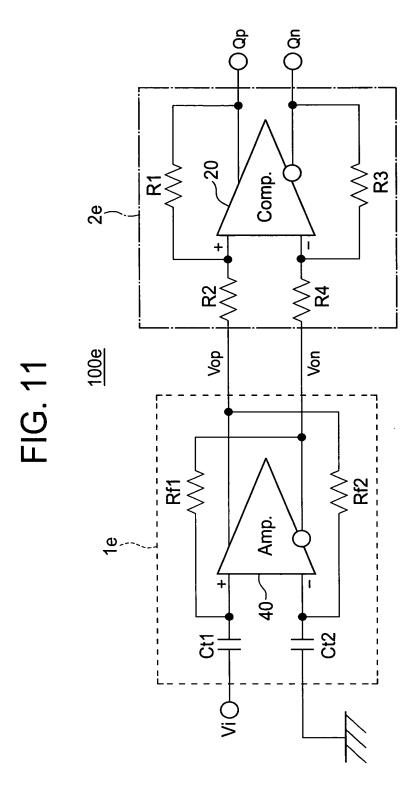
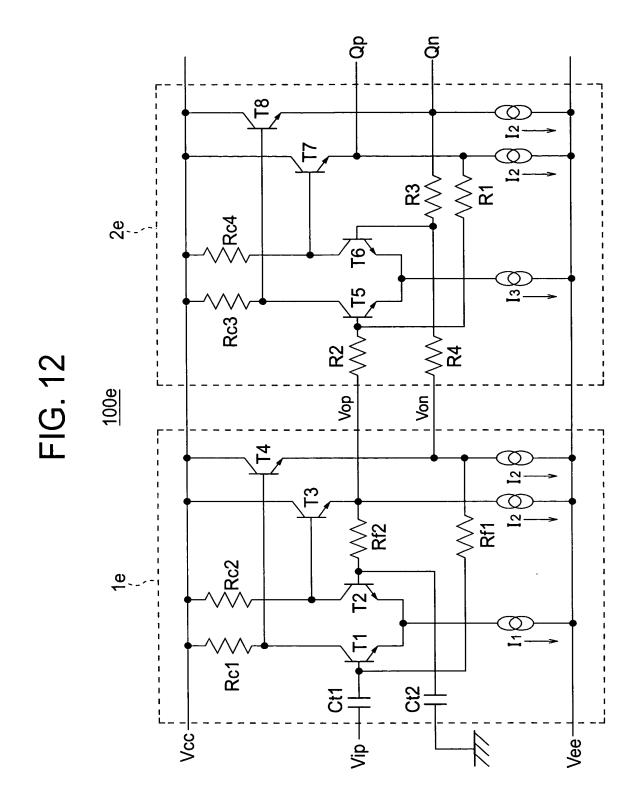


FIG. 9









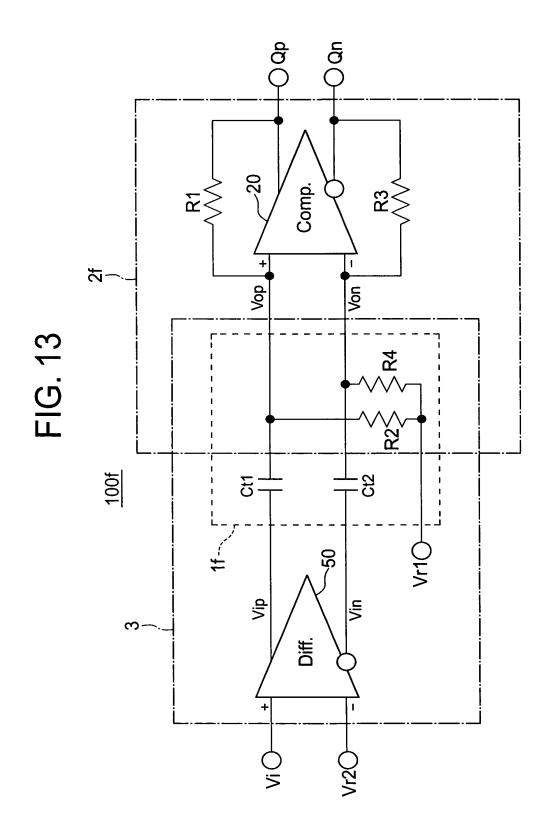
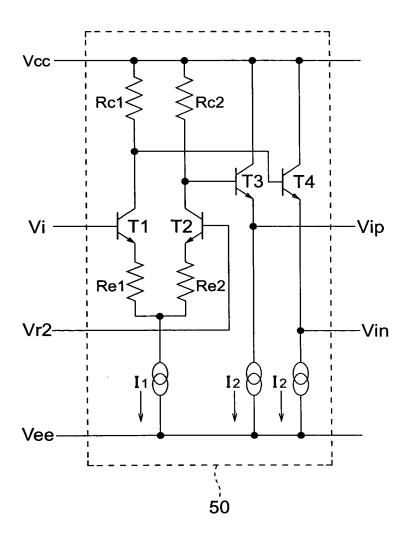
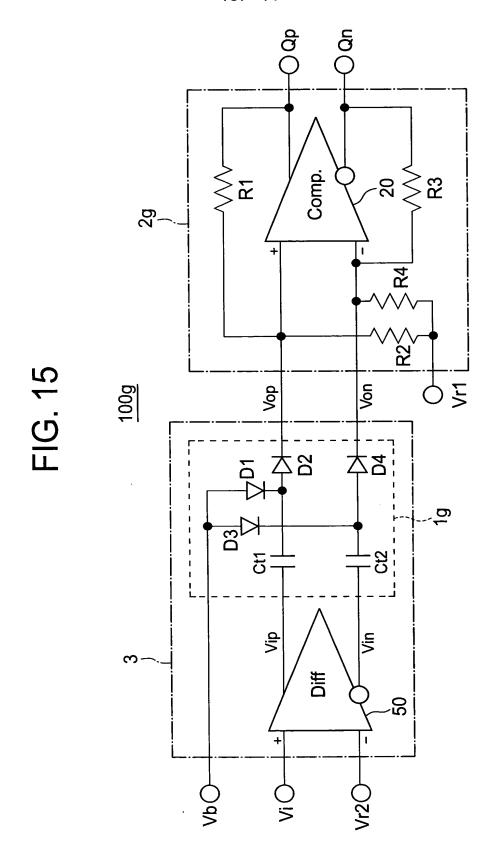
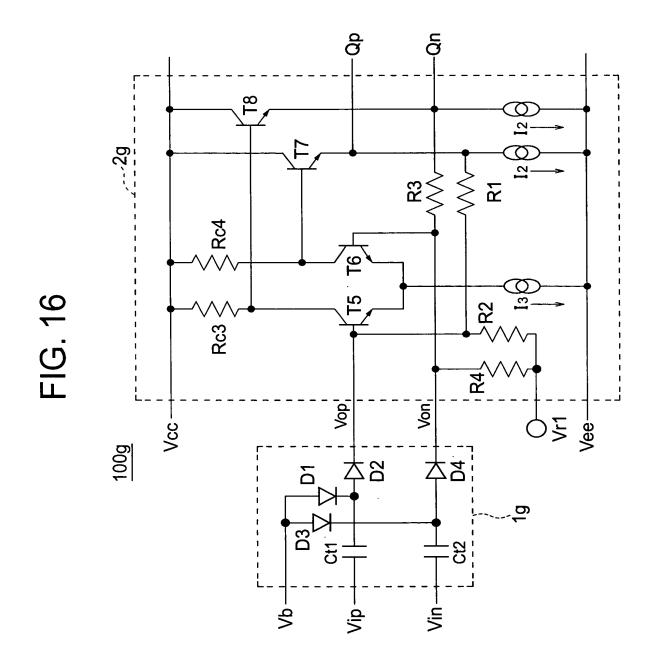
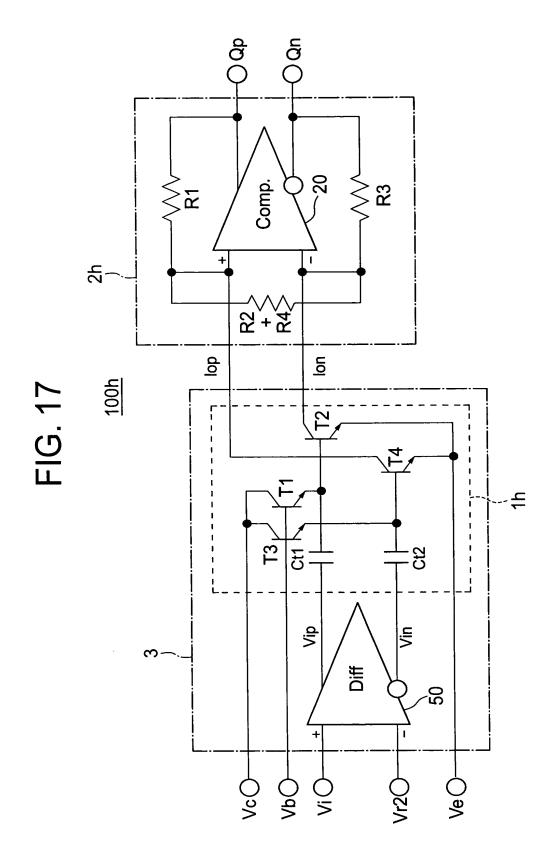


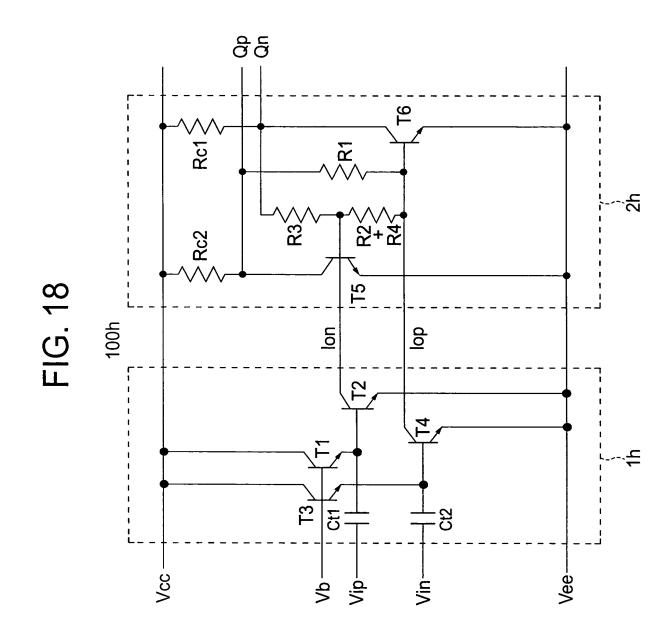
FIG. 14

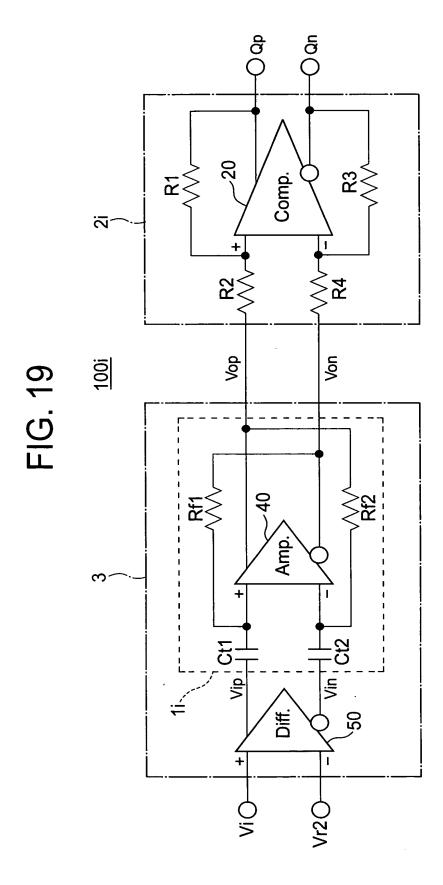


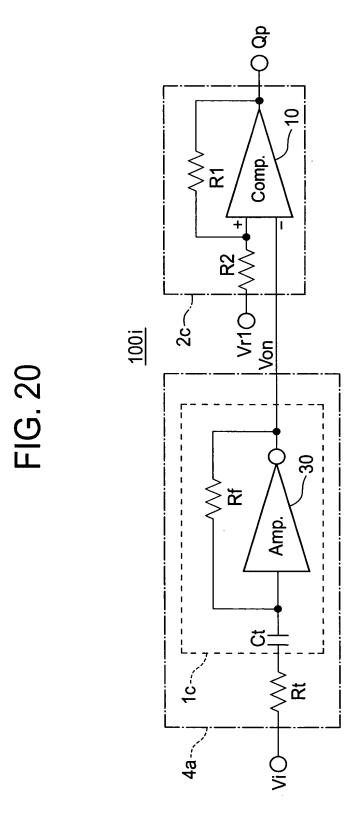












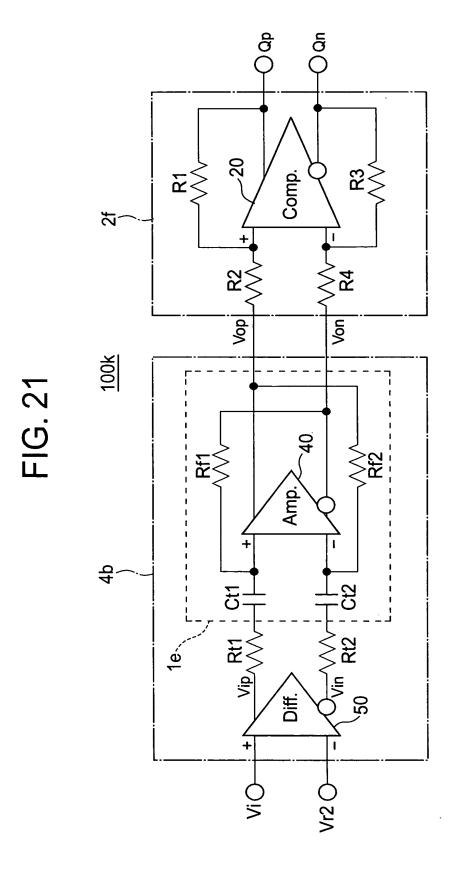
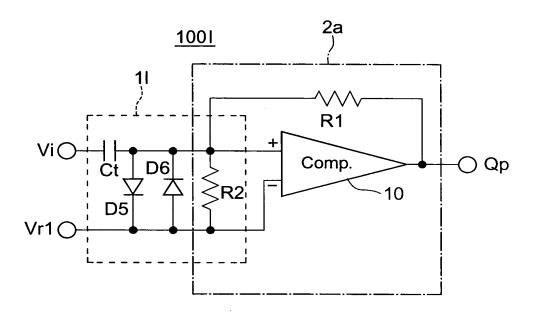
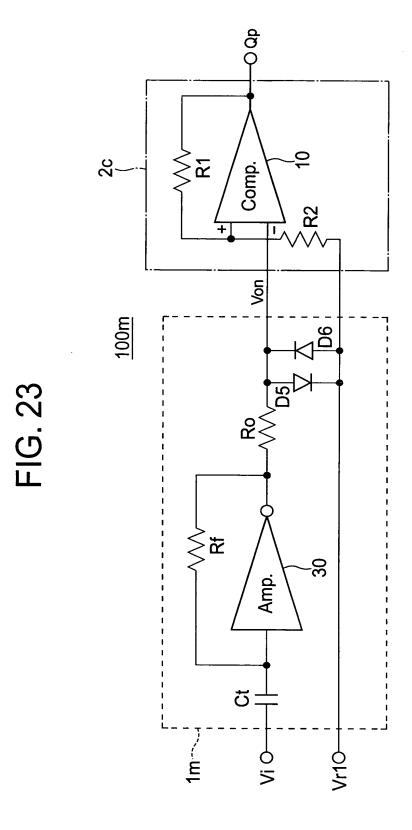
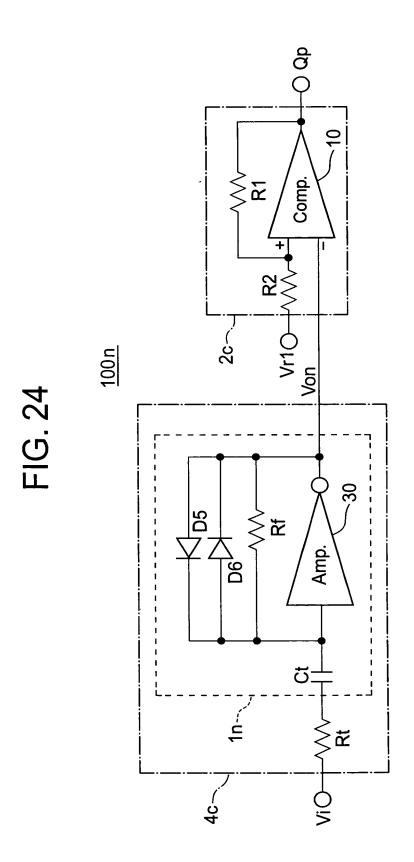
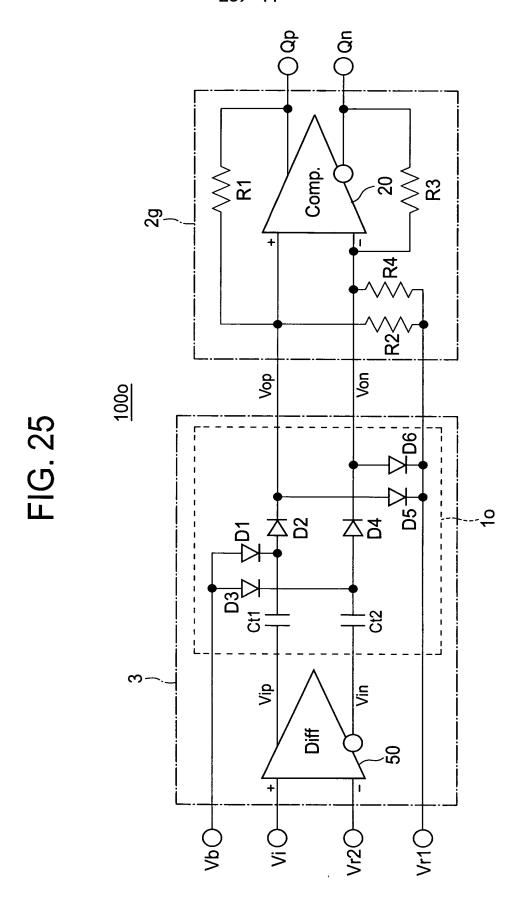


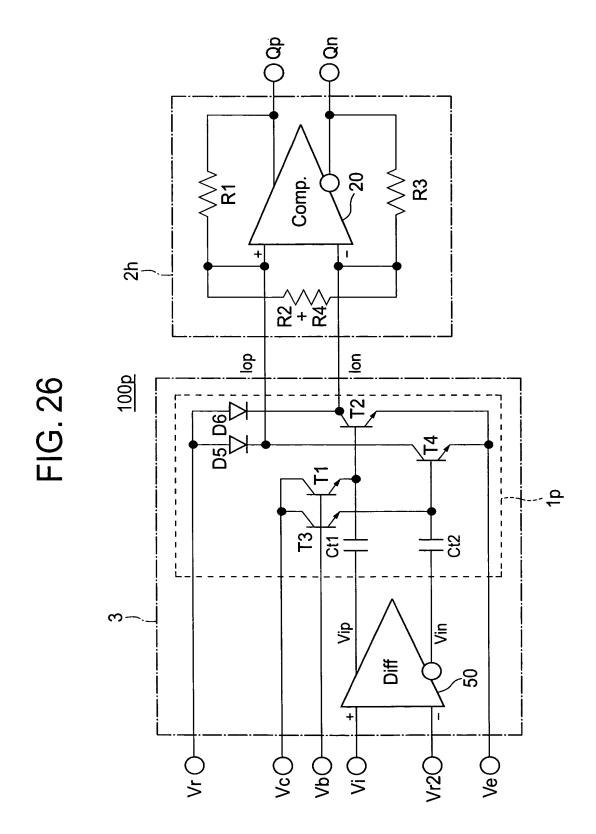
FIG. 22

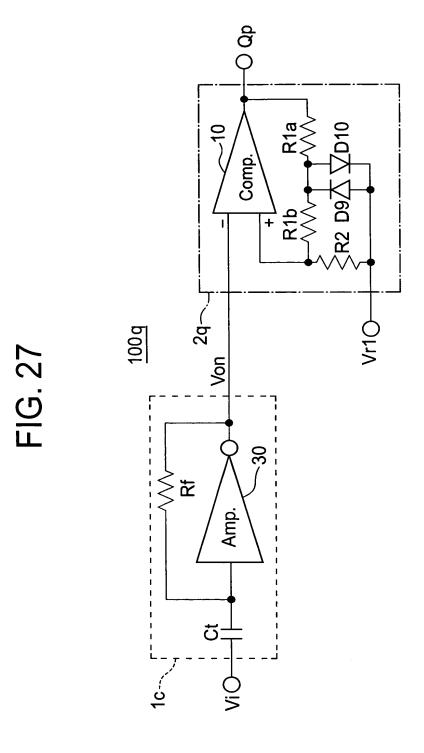












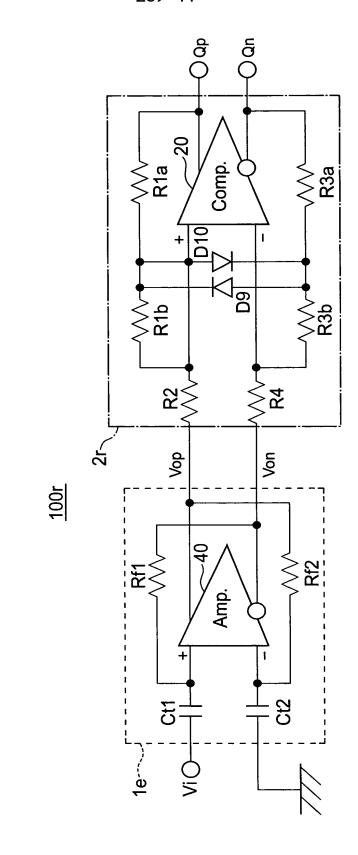
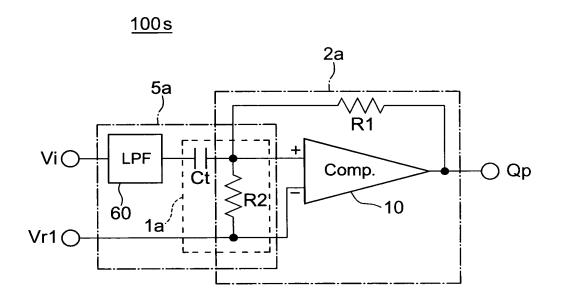
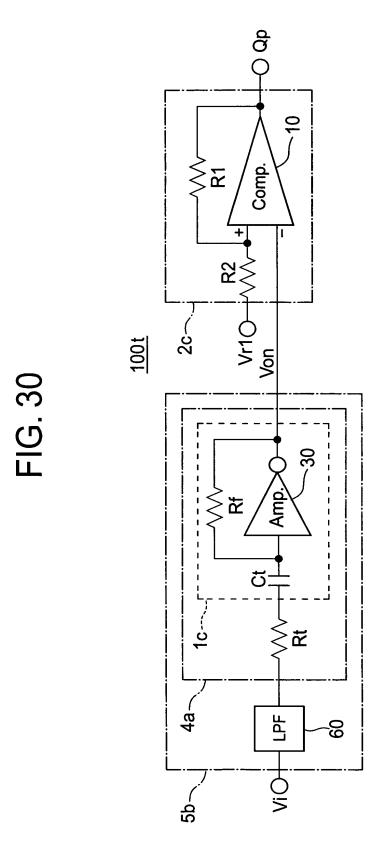
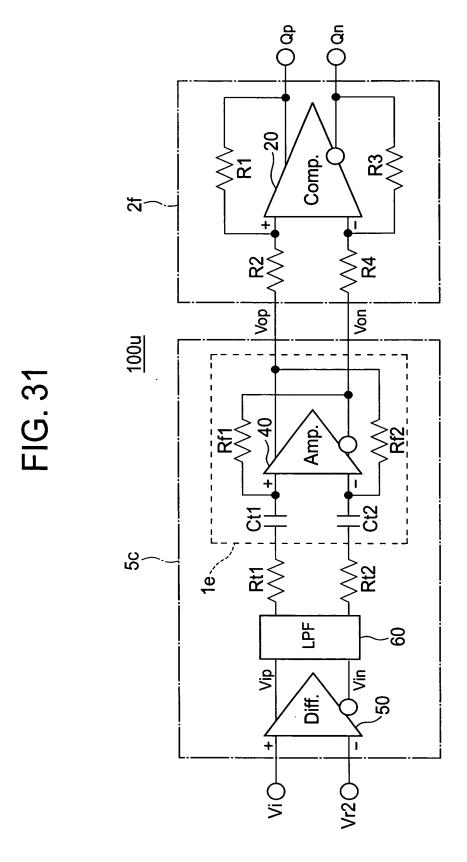


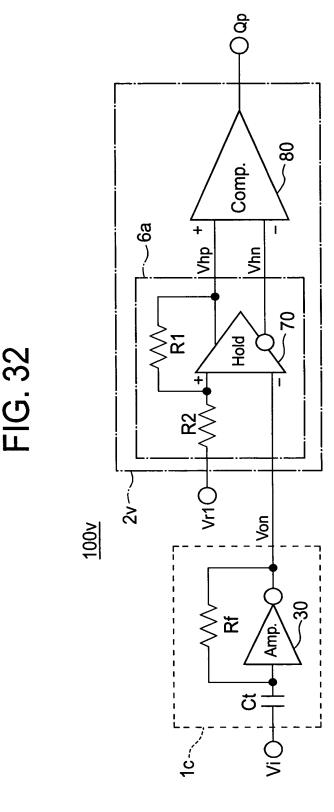
FIG. 28

FIG. 29









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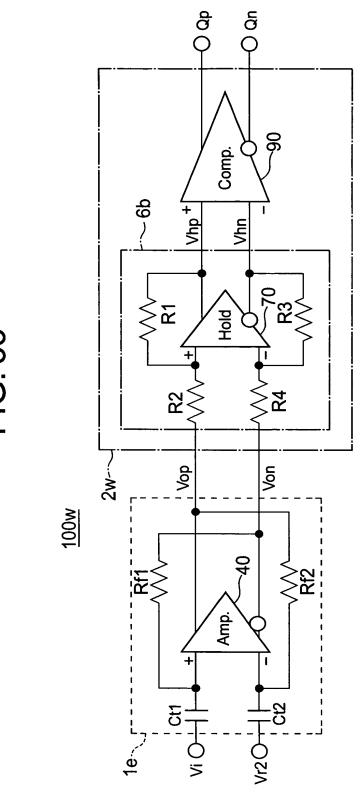
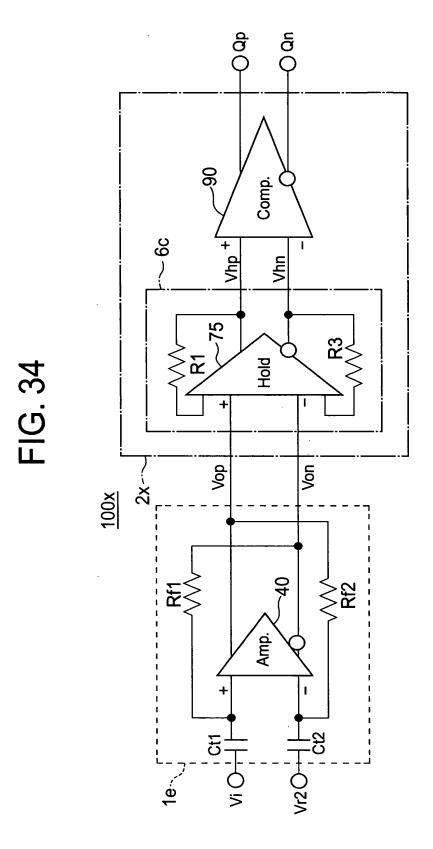
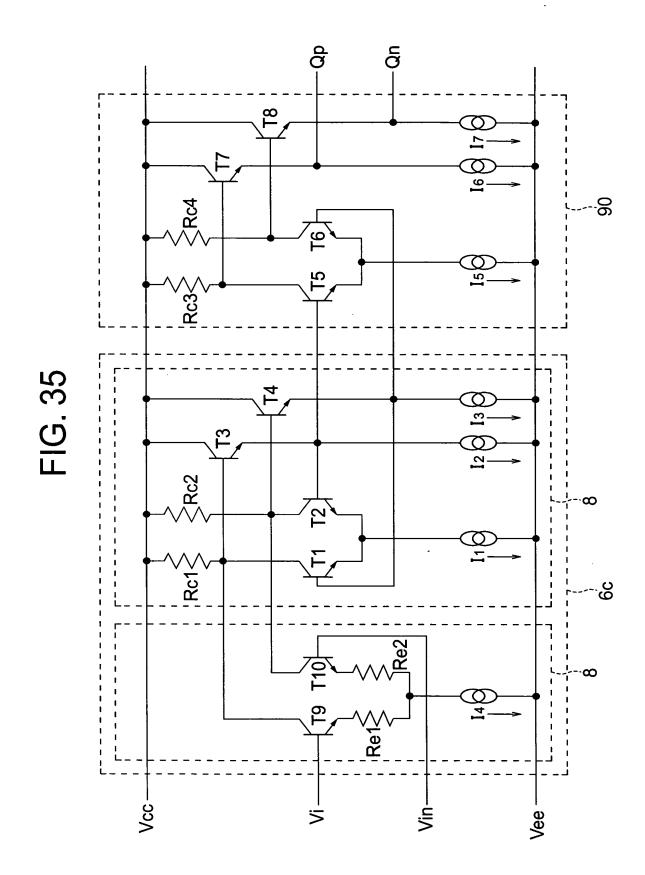
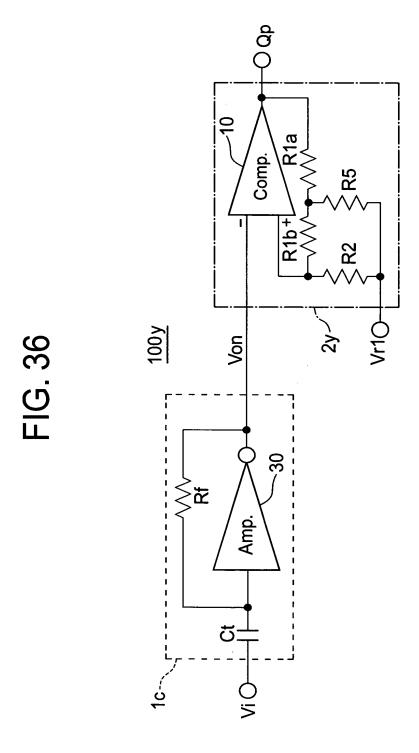


FIG. 33







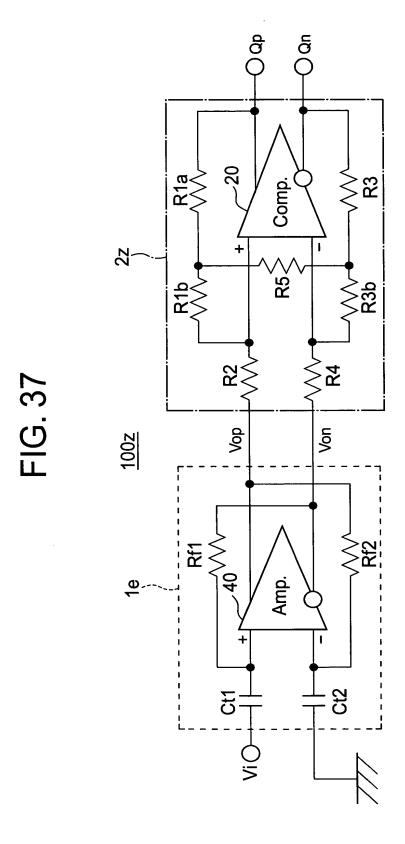


FIG. 38A

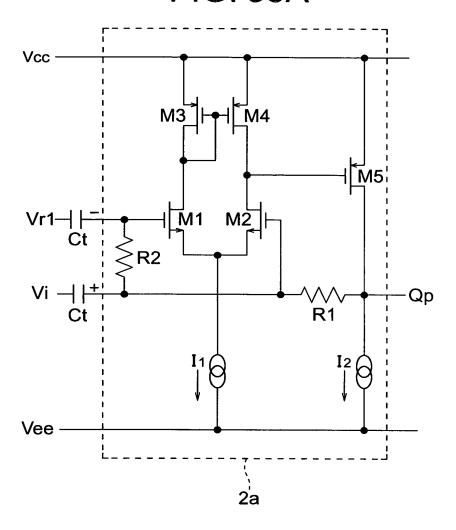
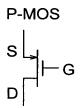


FIG. 38B

N-MOS G | D S

FIG. 38C



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## FIG. 39

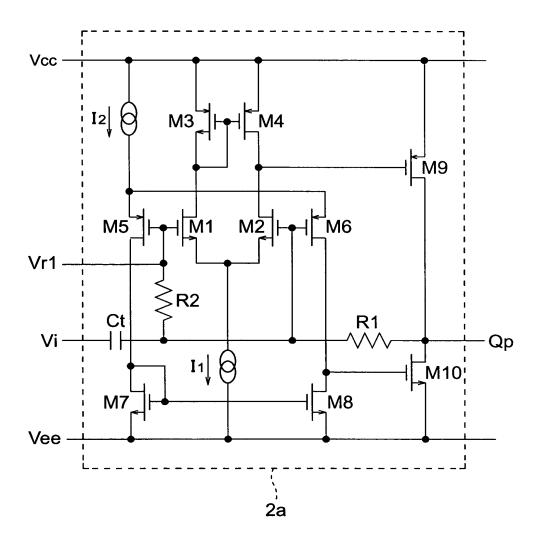


FIG. 40

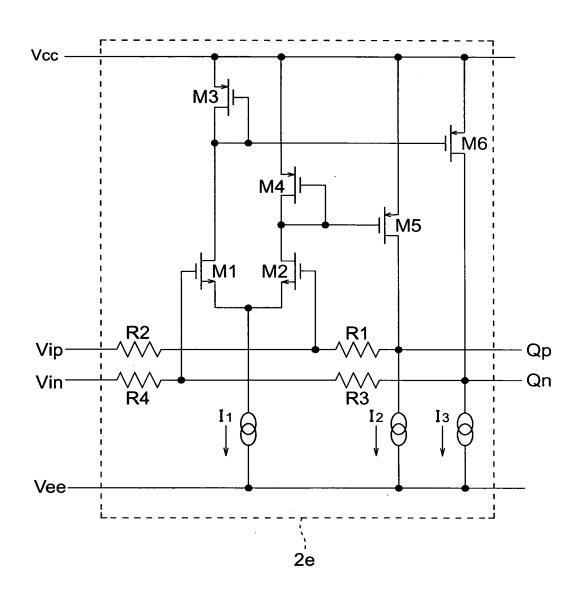


FIG. 41

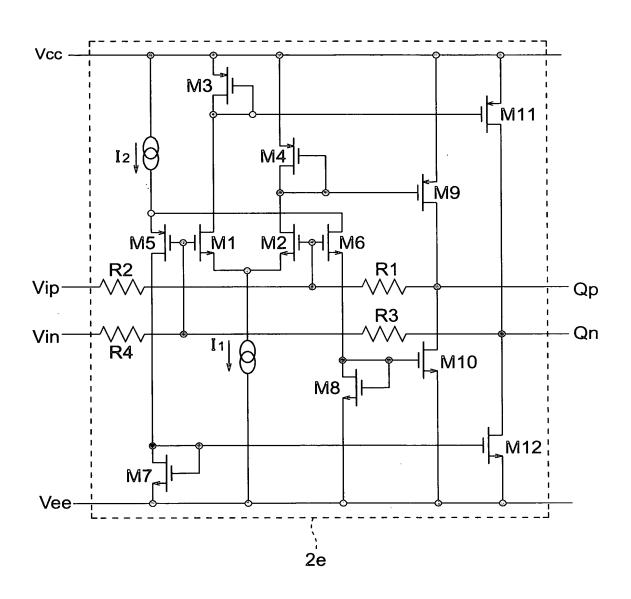


FIG. 42

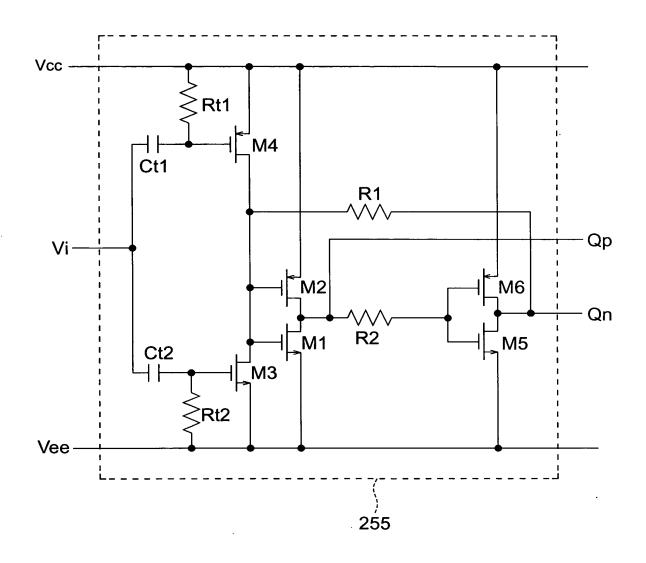


FIG. 43

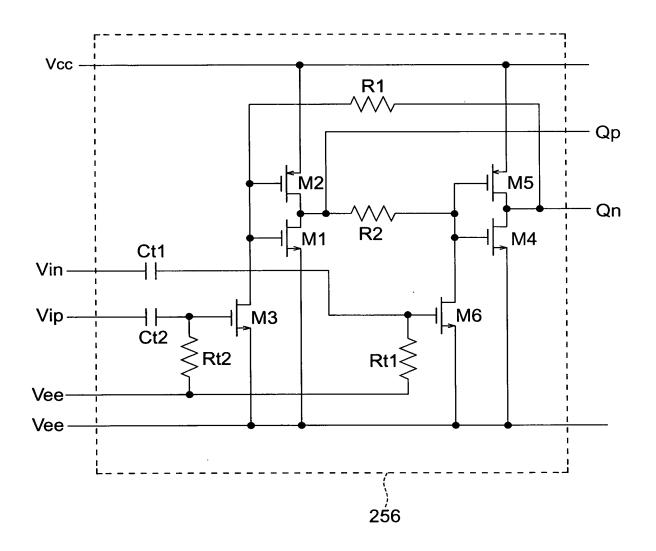


FIG. 44

